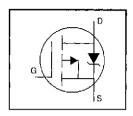


# HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- · Repetitive Avalanche Rated
- P-Channel
- 175°C Operating Temperature
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements



$$V_{DSS} = -60V$$

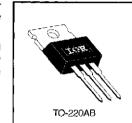
$$R_{DS(on)} = 0.14\Omega$$

$$I_{D} = -18A$$

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



## **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, VGS @ -10 V	-18	
ID @ Tc = 100°C	Continuous Drain Current, VGS @ -10 V	-13	A
I <sub>DM</sub>	Pulsed Drain Current ⊕	-72	
P <sub>D</sub> @ T <sub>C</sub> ≈ 25°C	Power Dissipation	88	W
-	Linear Derating Factor	0.59	W/°C
Vas	Gate-to-Source Voltage	±20	V
Eas	Single Pulse Avalanche Energy ②	370	mJ
I <sub>AR</sub>	Avalanche Current ①	-18	, A
EAR	Repetitive Avalanche Energy ①	8.8	mJ
dv/dt	Peak Diode Recovery dv/dt ③	-4.5	V/ns
ŢJ	Operating Junction and	-55 to +175	i
Tsrs	Storage Temperature Range	·	°C '
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf-in (1.1 N-m)	1

#### Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
Raic	Junction-to-Case	_	_	1.7	
Recs	Case-to-Sink, Flat, Greased Surface		0.50	_	°C/W
R <sub>eJA</sub>	Junction-to-Ambient		-	62	

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## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	. Parameter	Min.	Тур.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-60	_	1	V	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.060	-	V/°C	Reference to 25°C, ID=-1mA
Ros(en)	Static Drain-to-Source On-Resistance	_	_	0.14	Ω	Ves=-10V, to=-11A @
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0		-4.0	٧	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA
g <sub>fs</sub>	Forward Transconductance	5.9	_	_	S	V <sub>DS</sub> =-25V, I <sub>D</sub> =-11A @
loss	Drain-to-Source Leakage Current		.—	-100	μÄ	V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V
IDSS	Dialii-10-30dice Leakage Cuitent	_	_	-500	μΑ	V <sub>DS</sub> =-48V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C
loss	Gate-to-Source Forward Leakage	_	_	-100	nΑ	V <sub>GS</sub> =-20V
IGS8	Gate-to-Source Reverse Leakage	_	_	100	Ĭ	V <sub>GS</sub> =20V
Qg	Total Gate Charge	_		34		I <sub>D</sub> =-18A
Q <sub>gs</sub>	Gate-to-Source Charge		_	9.9	nC	V <sub>DS</sub> =-48V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		_	16		V <sub>GS</sub> =-10V See Fig. 6 and 13 @
t <sub>d(on)</sub>	Turn-On Delay Time	1	18			V <sub>DD</sub> =-30V
tr	Rise Time	_	120	_	ns	I <sub>D</sub> =-18A
t <sub>d(off)</sub>	Turn-Off Delay Time	-	20			$R_{G}=12\Omega$
tr	Fall Time	_	58			R <sub>D</sub> =1.5Ω See Figure 10
L <sub>D</sub>	Internal Drain Inductance	_	4.5		nΗ	Between lead, 6 mm (0.25in.)
Ls	Internal Source Inductance		7,5	_		from package and center of die contact
Ciss	Input Capacitance		1100			V <sub>GS</sub> =0V
Coss	Output Capacitance	_	620	_	pF	V <sub>DS</sub> =-25V
Crss	Reverse Transfer Capacitance	_	100			f=1.0MHz See Figure 5

# Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Is	Continuous Source Current (Body Diode)	_	_	-18	A	MOSFET symbol showing the
Ism	Pulsed Source Current (Body Diode) ①		_	-72		integral reverse p-n junction diode.
Vsp	Diode Forward Voltage		. —	-6.3	٧	T <sub>J</sub> =25°C, I <sub>S</sub> =-18A, V <sub>GS</sub> =0V ®
t <sub>rr</sub>	Reverse Recovery Time		100	200	ns	TJ=25°C, IF=-18A
Qrr	Reverse Recovery Charge		0.28	0.52	μC	di/dt≃100A/μs ④
ton	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is neglegible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )			

#### Notes:

- ① Repetitive rating; pulse width limited by max, junction temperature (See Figure 11)
- ③ Isp≤-18A, di/dt≤170A/ $\mu$ s, Vpp≤V(BR)pss, TJ≤175°C
- ② V<sub>DD</sub>=-25V, starting T<sub>J</sub>=25°C, L=1.3mH R<sub>G</sub>=25 $\Omega$ , I<sub>AS</sub>=-18A (See Figure 12)
- ⓐ Pulse width ≤ 300  $\mu$ s; duty cycle ≤2%.

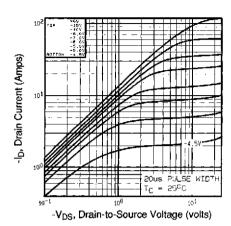


Fig 1. Typical Output Characteristics, Tc=25°C

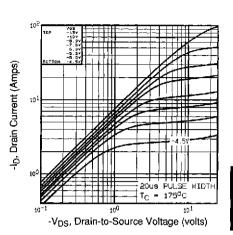


Fig 2. Typical Output Characteristics, Tc=175°C

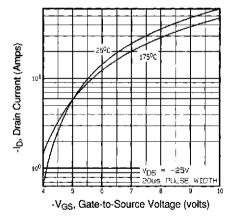


Fig 3. Typical Transfer Characteristics

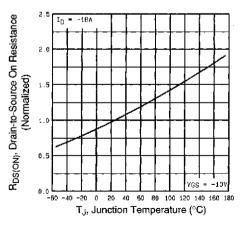


Fig 4. Normalized On-Resistance Vs. Temperature

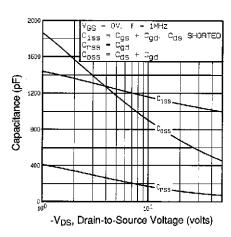


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

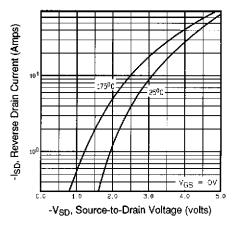


Fig 7. Typical Source-Drain Diode Forward Voltage

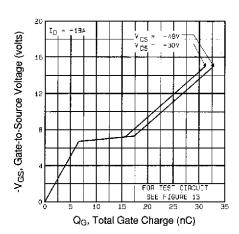


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

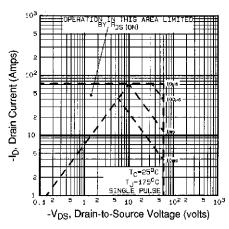


Fig 8. Maximum Safe Operating Area

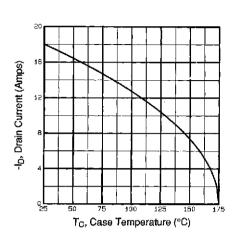


Fig 9. Maximum Drain Current Vs. Case Temperature

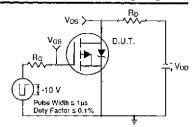


Fig 10a. Switching Time Test Circuit

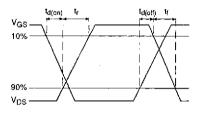


Fig 10b. Switching Time Waveforms

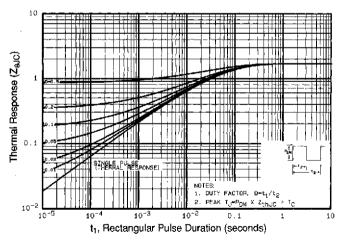


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

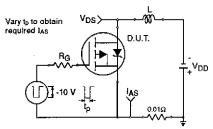


Fig 12a. Unclamped Inductive Test Circuit

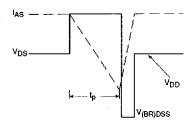


Fig 12b. Unclamped Inductive Waveforms

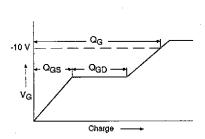


Fig 13a. Basic Gate Charge Waveform

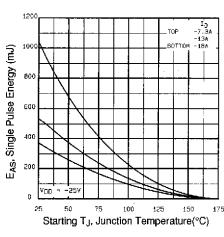


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

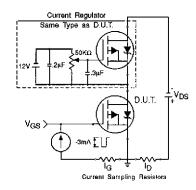


Fig 13b. Gate Charge Test Circuit

Appendix A: Figure 14, Peak Diode Recovery dv/dt Test Circuit - See page 1506

Appendix B: Package Outline Mechanical Drawing - See page 1509

Appendix C: Part Marking Information - See page 1516

Appendix E: Optional Leadforms- See page 1525





Vishay

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